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DESC FORM 193 SEP 87

\* U.S. GOVERNMENT PRINTING OFFICE: 1987 — 748-129/60911

5962-E528

1. SCO	PE		· · · · · · · · · · · · · · · · · · ·	
with 1.2.	.1 of MIL-STD-883, "Pr devices".	ovisions for the use	ements for class B micro of MIL-STD-883 in conju	nction with compliant
1.2 <u>Pa</u>	art number. The compl	ete part number shall	be as shown in the fol	lowing example:
	<u>5962-87673</u>	01	A	<u>C</u>   
	Drawing number	Device type (1.2.1)	Case outline (1.2.2)	Lead finish per MIL-M-38510
1.2.1	Device type. The dev	vice type shall identi	fy the circuit function	as follows:
	Device type	Generic number	Circuit func	tion
	01	DG180A	High-speed driver wit	h JFET switches
1.2.2 as follow		case outlines shall be	as designated in appen	dix C of MIL-M-38510, and
	Outline letter		Case outline	
	A C I	D-1 (14-lead	, .280" x .260" x .085" , .785" x .310" x .200" , .370" x .185"), can p	), dual-in-line package
1.3 A	bsolute maximum rating	<u>ıs</u> .		
Ye Ye Ye Ye Ci Ci Le Si	oltage, negative supplottage, input to logic oltage, reference supplottage, reference supplottage, negative supplottage, input to reference, source or drawarrent, all other pinsead temperature (solde torage temperature (torage temperature (tower dissipation (PD)).  Case A Case C	y to logic supply (V <sub>L</sub> supply (V <sub>L</sub> supply (V <sub>L</sub> to V <sub>IN</sub> )) bly to logic supply (V <sub>L</sub> to V <sub>IN</sub> ) to input (V <sub>IN</sub> to V <sub>I</sub> ) to reference supply (V <sub>R</sub> to V <sub>I</sub> ) in ering, 10 seconds)		8 V dc 8 V dc 8 V dc 27 V dc 20 V dc 200 mA 30 mA +300°C -65°C to +150°C +175°C 750 mW 825 mW

1/ Power ratings based on device mounted with all leads welded or soldered to PC board. Derate at +75°C the following cases: Case A at 10 mW/°C, Case C at 11 mW/°C, Case I at 6 mW/°C.

STANDARDIZED MILITARY DRAWING	SIZE A		5962	2-87673	
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444		REVISION LEVEL	•	SHEET	2

appendix C

1.4 Recommended operating conditions.

### 2. APPLICABLE DOCUMENTS

2.1 Government specification and standard. Unless otherwise specified, the following specification and standard, of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

**SPECIFICATION** 

MILITARY

MIL-M-38510 - Microcircuits, General Specification for.

**STANDARD** 

**MILITARY** 

MIL-STD-883 - Test Methods and Procedures for Microelectronics.

(Copies of the specification and standard required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.

# 3. REQUIREMENTS

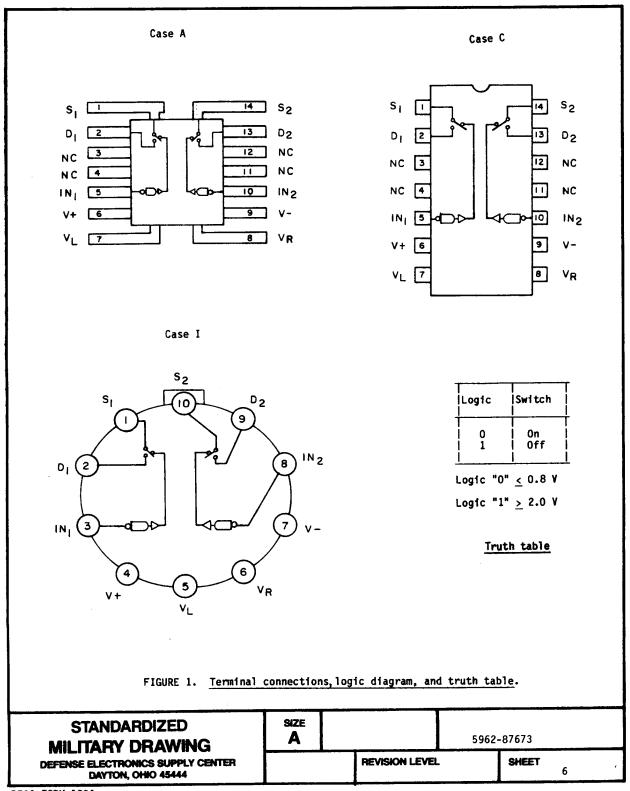
- 3.1 Item requirements. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.
- $3.2\,$  Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.
  - 3.2.1 Terminal connections. The terminal connections shall be as specified on figure 1.
  - 3.2.2 Logic diagram. The logic diagram shall be as specified on figure 1.
  - 3.2.3 Truth table. The truth table shall be as specified on figure 1.
  - 3.2.4 Case outlines. The case outlines shall be in accordance with 1.2.2 herein.
- 3.3 Electrical performance characteristics. Unless otherwise specified, the electrical performance characteristics are as specified in table I and apply over the full ambient operating temperature range.
  - 3.3.1 AC test circuit. AC test circuits shall be as specified on figure 2.
- 3.4 Marking. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the part number listed in 1.2 herein. In addition, the manufacturer's part number may also be marked as listed in 6.4 herein.

STANDARDIZED MILITARY DRAWING	SIZE A	5962-87673			1	
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444			REVISION LEVEL		SHEET	3

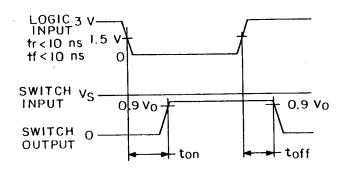
Test	Symbol	Conditions -55°C < T <sub>A</sub> < +125°C	Group A    subgroups	Limi	Unit	
	<u> </u>	V+ = 15 V, $V = -15$ V, $V_{\parallel} = 5$ V (unless otherwise specified)		Min	Max	<u> </u>
Resistance (on) drain-to-source	R <sub>DS</sub>	$V_{D} = -7.5 \text{ V}$ $I_{S} = -10 \text{ mA}$ $V_{IN} = 0.8 \text{ V}$	1, 2, 3	2	10	Ω
Source leakage $ I_{S(0FF)} V^{+} = 10 \text{ V}, V_{-} = -20 \text{ V}$ current (off) $ V_{D}  = -10 \text{ V}, V_{S} = 10 \text{ V},$		V+ = 10 V, V- = -20 V  Vn = -10 V, V <sub>S</sub> = 10 V,	1	-10.0	10.0	   nA 
		V <sub>IN</sub> = 2 V	2, 3	-1000	1000	
	i -	V <sub>D</sub> = -7.5 V, V <sub>S</sub> = 7.5 V,   V <sub>TN</sub> = 2 V	1	-10.0	10.0	   
•	İ	10   :	2, 3	-1000	1000	[     
Drain leakage current (off)	I <sub>D</sub> (OFF)	V <sub>D</sub> = 7.5 V, V <sub>S</sub> = -7.5 V,	1 1	-10.0	10.0	]   
	İ	In   	2, 3	-1000	1000	[     
		$ V^{+}  = 10 \text{ V}, V^{-}  = -20 \text{ V}$ $ V_{D}  = 10 \text{ V}, V_{S}  = -10 \text{ V},$	1	-10.0	10.0	   
	İ	V <sub>IN</sub> = 2 V	2, 3	-1000	1000	T
Channel leakage current (on)	ID(ON)+	V <sub>S</sub> = V <sub>D</sub> = -7.5 V,   V <sub>IN</sub> = 0.8 V	1 1	-2.0	2.0	T   <u> </u>
current (on)	-5(ON)	114	2, 3	-200	200	T !
Low level input current	IIL	V <sub>IN</sub> under test = 0 V	1, 2, 3	-250	10.0	μ.
High level input current	IIH	V <sub>IN</sub> under test = 5 V	1	-10.0	10.0	 
	1	1	2,3	-20	i 20	

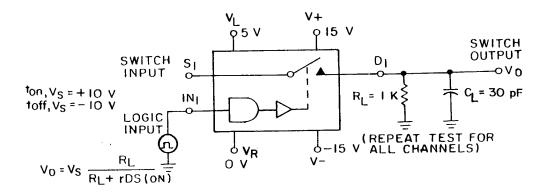
STANDARDIZED MILITARY DRAWING	SIZE A		5	5962-87673		
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444		REVIS	ION LEVEL	SHEET 4		

Test	Symbol	Cond	itions <pre><pre>+125°C</pre></pre>	  Group A    subgroups	Limit	Unit	
		$-55^{\circ}C < T_A < +125^{\circ}C$   $V^{+} = 15 V$ , $V^{-} = -15 V$ , $V_{L} = 5 V$   (unless otherwise specified)			Min   Max		<u> </u>
Positive supply	I <sub>CC+</sub>	VIN = O V		1		1.5	mA
current	"			2		1.5	<u> </u>
		! [		3		2.5	<u> </u>
		  V <sub>IN</sub> = 5 V		1		1.5	<u> </u>
				2	<u></u>	1.5	<u> </u>
	!	!		3		2.5	<u> </u>
Negative supply	I <sub>CC</sub> -	V <sub>IN</sub> = 5 V		1	-5.0		1
current	""			2	-5.0		<del> </del>
		<u> </u>		3	-8.0		<u> </u>
		V <sub>IN</sub> = 0 V		1	-5.0		<u> </u>
				2	-5.0		<u> </u>
				3	-8.0		<u> </u>
Logic supply	I <sub>L</sub>	V <sub>IN</sub> = 0 V and	V <sub>IN</sub> = 5 V	1		4.5	<u> </u>
current	-			2		4.5	<u> </u>
				3		7.5	<u> </u>
Reference supply	IR	$V_{IN} = 0 V$ and	V <sub>IN</sub> = 5 V	1 1	-2.0		1
current	[ [			2	-2.0		<u> </u>
				3	-2.5		<u> </u>
Functional tests		See 4.3.1c		7 1			<del>-  </del>
Turn on time	ton	  See figure 2		9		300	_  ns
				10,11 1/		450	İ
Turn off time	toff			9 [		250	
	011			10,11 1/		   350	
1/ Guaranteed if	not test	ed.					_!
STANDARDIZED MILITARY DRAWING			SIZE A	:	5962-87673		
DEFENSE ELECTI		PPLY CENTER	RE	VISION LEVEL	s	SHEET 5	



Logic input for off to on condition





 $V_0$  is the steady state output with the switch on. Feedthrough via switch capacitance may result in spikes at the leading and trailing edge of the output waveform. Switch output waveform shown for  $V_S$  = constant with logic input waveform as shown. Note that  $V_S$  may be + or - as per switching time test circuit.

FIGURE 2. AC switching diagram.

# STANDARDIZED MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444 SIZE A 5962-87673 REVISION LEVEL SHEET 7

- 3.5 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in 6.4. The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply shall state that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein.
- 3.6 Certificate of conformance. A certificate of conformance as required in MIL-STD-883 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.
- 3.7 Notification of change. Notification of change to DESC-ECS shall be required in accordance with MIL-STD-883 (see 3.1 herein).
- 3.8 Verification and review. DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.
  - 4. QUALITY ASSURANCE PROVISIONS
- 4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).
- 4.2 Screening. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:
  - a. Burn-in test, method 1015 of MIL-STD-883.
    - Test conditions A or C using the circuit submitted with the certificate of compliance (see 3.5 herein).
    - (2)  $T_A = +125^{\circ}C$ , minimum.
  - b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.
- 4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.
  - 4.3.1 Group A inspection.
    - a. Tests shall be as specified in table II herein.
    - b. Subgroups 4, 5, 6, and 8 of method 5005 of MIL-STD-883 shall be omitted.
    - c. Subgroup 7 tests shall include verification of the truth table.
  - 4.3.2 Groups C and D inspections.
    - a. End-point electrical parameters shall be as specified in table II herein.
    - b. Steady-state life test conditions, method 1005 of MIL-STD-883.
      - Test condition A or C using the circuit submitted with the certificate of compliance (see 3.5 herein).
      - (2)  $T_A = +125^{\circ}C$ , minimum.
      - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

STANDARDIZED MILITARY DRAWING	SIZE A		5 <b>96</b> 2-	87673	
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444		REVISION LEVEL	•	SHEET	8

# TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups (per method 5005, table I)
   Interim electrical parameters   (method 5004)	1
Final electrical test parameters   (method 5004)	1*,2,3,7,9
Group A test requirements   (method 5005)	   1,2,3,7,9,
Groups C and D end-point   electrical parameters   (method 5005)	1

\* PDA applies to subgroup 1.

\*\* Subgroups 10 and 11, if not tested, shall be guaranteed to the limits as specified in table I.

## 5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.

# 6. NOTES

- 6.1 Intended use. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.
- 6.2 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.
- 6.3 Comments. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, or telephone 513-296-5375.

STANDARDIZED
MILITARY DRAWING

DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444

 6.4 Approved sources of supply. Approved sources of supply are listed herein. Additional sources will be added as they become available. The vendors listed herein have agreed to this drawing and a certificate of compliance (see 3.5 herein) has been submitted to DESC-ECS.

Military drawing part number	Vendor     CAGE     number	Vendor similar part number <u>1</u> /
5962-8767301AX	17856 32293	DG180AP/883 DG180AP/883
5962-8767301CX	17856 32293	DG180AL/883 DG180AL/883
5962-8767301IX	17856 32293	DG180AA/883 DG180AA/883

Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE number	Vendor name and address
17856	Siliconix, Incorporated 2201 Laurelwood Road Santa Clara, CA 95054
32293	Intersil, Incorporated 10600 Ridgeview Court Cuperting, CA 95014

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MILITARY DRAWING
DEFENSE ELECTRONICS SUPPLY CENTER

DAYTON, OHIO 45444

DESC FORM 193A SEP 87

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